

DOSEMI**IGBT****DG160A08TDFS****750V/160A IGBT with Diode****General Description**

DOSEMI IGBT Power Discrete provides ultra low conduction loss

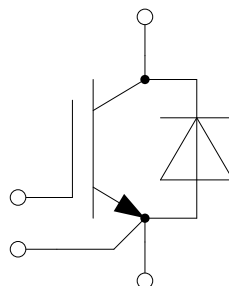
They are designed for the applications such as solar power and on-board charger.

Features

- Low $V_{CE(sat)}$ IGBT technology
- Maximum junction temperature 175°C
- $V_{CE(sat)}$ with positive temperature coefficient
- Fast & soft reverse recovery anti-parallel FWD

Typical Applications

- Solar power
- UPS
- OBC

Equivalent Circuit Schematic

Type	Package	Marking	Shipping
DG160A08TDFS	TO-247PLUS-4L	DG160A08TDFS	30Units/Tube

Absolute Maximum Ratings $T_C=25^{\circ}\text{C}$ unless otherwise noted**IGBT**

Symbol	Description	Value	Unit
V_{CES}	Collector-Emitter Voltage	750	V
V_{GES}	Gate-Emitter Voltage Transient Gate-Emitter Voltage	± 20 ± 30	V
I_C	Collector Current @ $T_C=25^{\circ}\text{C}$ @ $T_C=100^{\circ}\text{C}$	200 ⁽¹⁾ 160	A
I_{CM}	Pulsed Collector Current t_p limited by T_{vjmax}	320	A
P_D	Maximum Power Dissipation @ $T_{vj}=175^{\circ}\text{C}$	625	W

Diode

Symbol	Description	Value	Unit
V_{RRM}	Repetitive Peak Reverse Voltage	750	V
I_F	Diode Continuous Forward Current @ $T_C=25^{\circ}\text{C}$ @ $T_C=100^{\circ}\text{C}$	200 ⁽¹⁾ 160	A
I_{FM}	Diode Pulsed Current t_p limited by T_{vjmax}	320	A

Discrete

Symbol	Description	Values	Unit
T_{vjop}	Operating Junction Temperature	-40 to +175	$^{\circ}\text{C}$
T_{STG}	Storage Temperature Range	-55 to +150	$^{\circ}\text{C}$
T_S	Soldering Temperature, 1.6mm from case for 10s	260	$^{\circ}\text{C}$

(1) limited by bondwire

IGBT Characteristics $T_C=25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{CE(sat)}$	Collector to Emitter Saturation Voltage	$I_C=160\text{A}, V_{GE}=15\text{V}, T_{vj}=25^{\circ}\text{C}$		1.45	1.90	V
		$I_C=160\text{A}, V_{GE}=15\text{V}, T_{vj}=150^{\circ}\text{C}$		1.75		
		$I_C=160\text{A}, V_{GE}=15\text{V}, T_{vj}=175^{\circ}\text{C}$		1.80		
$V_{GE(th)}$	Gate-Emitter Threshold Voltage	$I_C=3.2\text{mA}, V_{CE}=V_{GE}, T_{vj}=25^{\circ}\text{C}$	3.5	4.0	4.5	V
I_{CES}	Collector Cut-Off Current	$V_{CE}=V_{CES}, V_{GE}=0\text{V}, T_{vj}=25^{\circ}\text{C}$			200	μA
I_{GES}	Gate-Emitter Leakage Current	$V_{GE}=V_{GES}, V_{CE}=0\text{V}, T_{vj}=25^{\circ}\text{C}$			100	nA
R_{Gint}	Internal Gate Resistance			0		Ω
C_{ies}	Input Capacitance	$V_{CE}=25\text{V}, f=100\text{kHz}, V_{GE}=0\text{V}$		6.96		nF
C_{oes}	Output Capacitance			0.31		nF
C_{res}	Reverse Transfer Capacitance			0.03		nF
Q_G	Gate Charge	$V_{GE}=0\dots+15\text{V}$		0.24		μC
$t_{d(on)}$	Turn-On Delay Time	$V_{CC}=400\text{V}, I_C=160\text{A}, R_{Gon}=27\Omega, R_{Goff}=20\Omega, L_S=40\text{nH}, V_{GE}=0/+15\text{V}, T_{vj}=25^{\circ}\text{C}$		62		ns
t_r	Rise Time			60		ns
$t_{d(off)}$	Turn-Off Delay Time			470		ns
t_f	Fall Time			54		ns
E_{on}	Turn-On Switching Loss			8.20		mJ
E_{off}	Turn-Off Switching Loss			1.07		mJ
$t_{d(on)}$	Turn-On Delay Time	$V_{CC}=400\text{V}, I_C=160\text{A}, R_{Gon}=27\Omega, R_{Goff}=20\Omega, L_S=40\text{nH}, V_{GE}=0/+15\text{V}, T_{vj}=150^{\circ}\text{C}$		46		ns
t_r	Rise Time			66		ns
$t_{d(off)}$	Turn-Off Delay Time			523		ns
t_f	Fall Time			57		ns
E_{on}	Turn-On Switching Loss			9.80		mJ
E_{off}	Turn-Off Switching Loss			1.79		mJ
$t_{d(on)}$	Turn-On Delay Time	$V_{CC}=400\text{V}, I_C=160\text{A}, R_{Gon}=27\Omega, R_{Goff}=20\Omega, L_S=40\text{nH}, V_{GE}=0/+15\text{V}, T_{vj}=175^{\circ}\text{C}$		44		ns
t_r	Rise Time			71		ns
$t_{d(off)}$	Turn-Off Delay Time			538		ns
t_f	Fall Time			61		ns
E_{on}	Turn-On Switching Loss			9.83		mJ
E_{off}	Turn-Off Switching Loss			1.89		mJ

Diode Characteristics $T_C=25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V_F	Diode Forward Voltage	$I_F=160\text{A}, V_{GE}=0\text{V}, T_{vj}=25^\circ\text{C}$		1.65	2.10	V
		$I_F=160\text{A}, V_{GE}=0\text{V}, T_{vj}=150^\circ\text{C}$		1.65		
		$I_F=160\text{A}, V_{GE}=0\text{V}, T_{vj}=175^\circ\text{C}$		1.65		
t_{rr}	Diode Reverse Recovery Time	$V_R=400\text{V}, I_F=160\text{A},$ $-di/dt=2500\text{A}/\mu\text{s}, L_S=40\text{nH},$ $V_{GE}=0\text{V}, T_{vj}=25^\circ\text{C}$		127		ns
Q_r	Recovered Charge			7.25		μC
I_{RM}	Peak Reverse Recovery Current			104		A
E_{rec}	Reverse Recovery Energy			0.52		mJ
t_{rr}	Diode Reverse Recovery Time	$V_R=400\text{V}, I_F=160\text{A},$ $-di/dt=2310\text{A}/\mu\text{s}, L_S=40\text{nH},$ $V_{GE}=0\text{V}, T_{vj}=150^\circ\text{C}$		201		ns
Q_r	Recovered Charge			13.4		μC
I_{RM}	Peak Reverse Recovery Current			125		A
E_{rec}	Reverse Recovery Energy			1.81		mJ
t_{rr}	Diode Reverse Recovery Time	$V_R=400\text{V}, I_F=160\text{A},$ $-di/dt=2244\text{A}/\mu\text{s}, L_S=40\text{nH},$ $V_{GE}=0\text{V}, T_{vj}=175^\circ\text{C}$		220		ns
Q_r	Recovered Charge			14.5		μC
I_{RM}	Peak Reverse Recovery Current			126		A
E_{rec}	Reverse Recovery Energy			2.04		mJ

Discrete Characteristics $T_C=25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Min.	Typ.	Max.	Unit
R_{thJC}	Junction-to-Case (per IGBT)			0.240	K/W
	Junction-to-Case (per Diode)			0.330	
R_{thJA}	Junction-to-Ambient		40		K/W

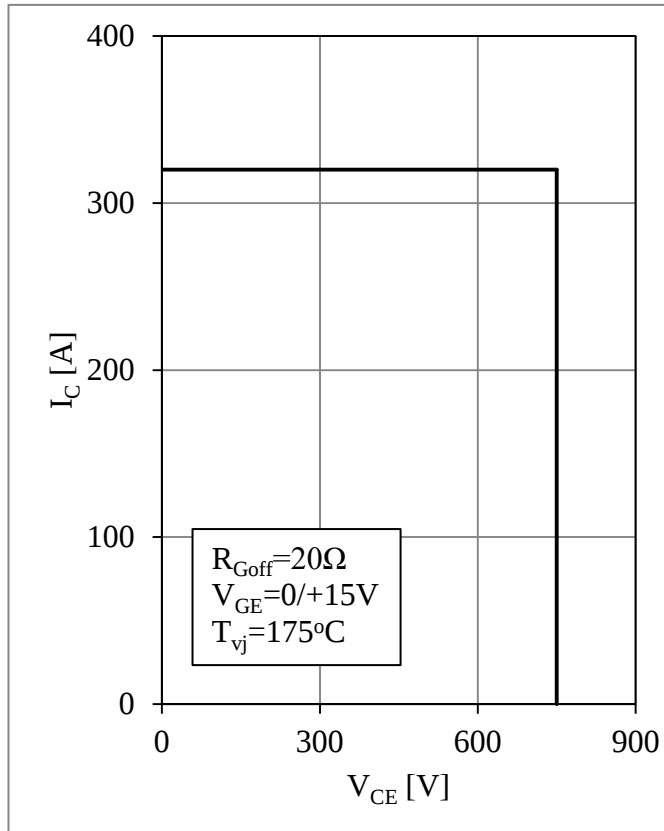


Fig 1. RBSOA

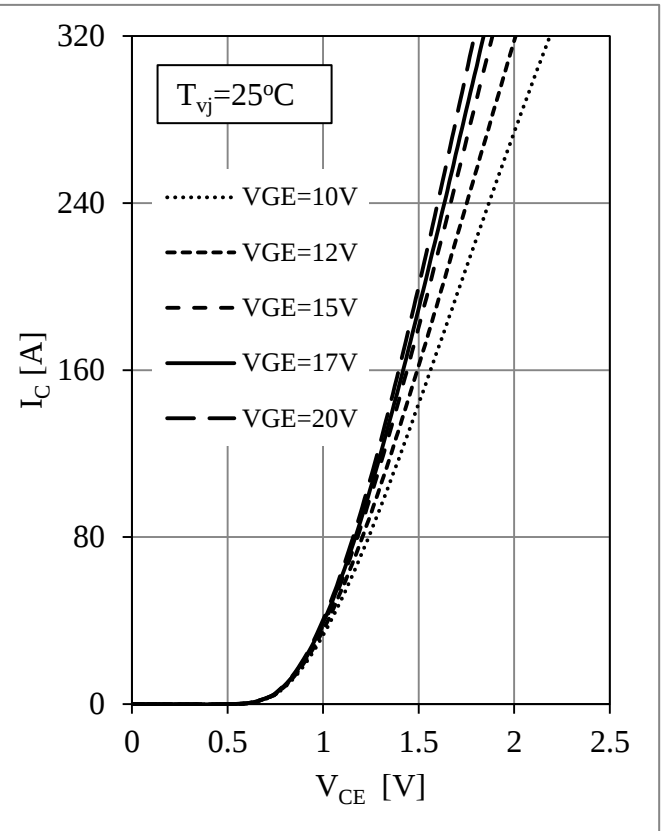


Fig 2. IGBT Output Characteristics

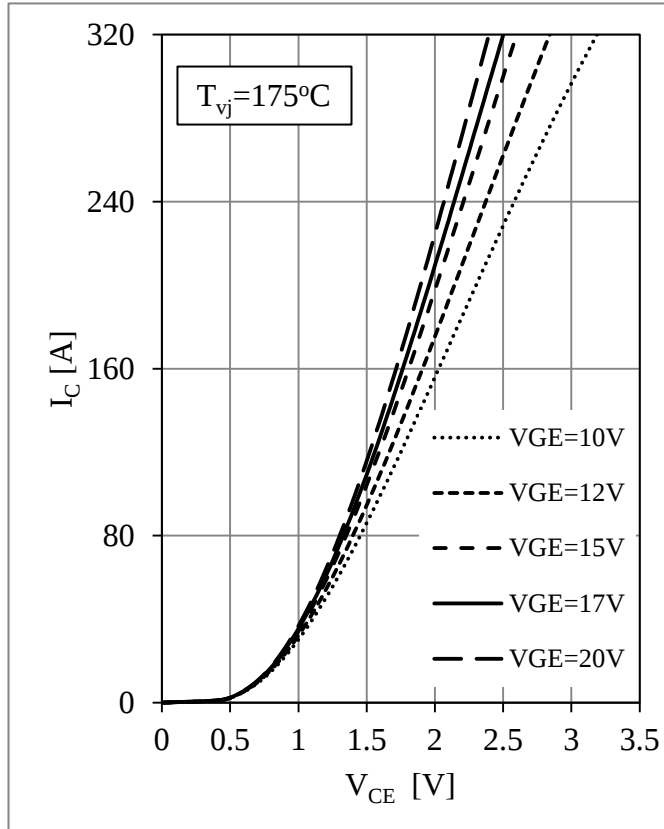


Fig 3. IGBT Output Characteristics

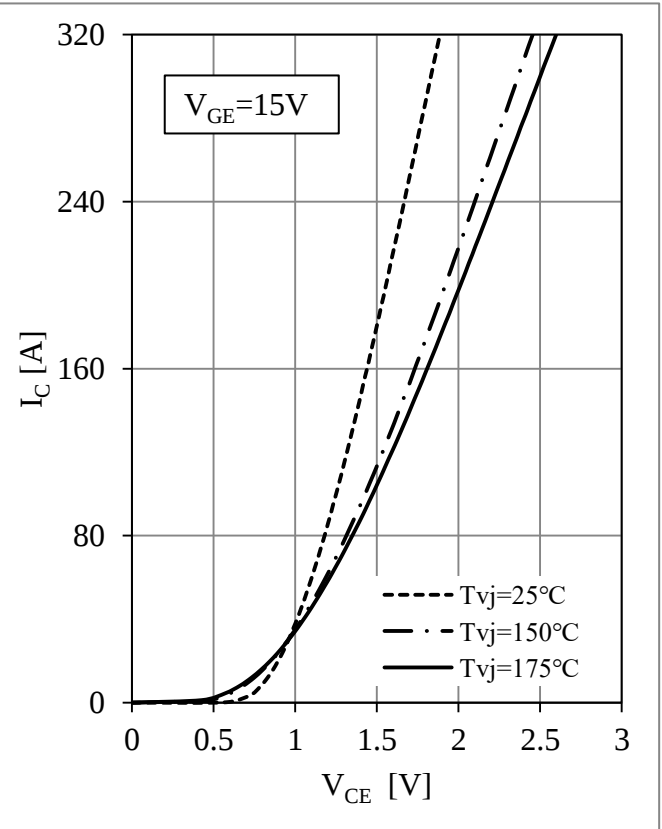


Fig 4. IGBT Output Characteristics

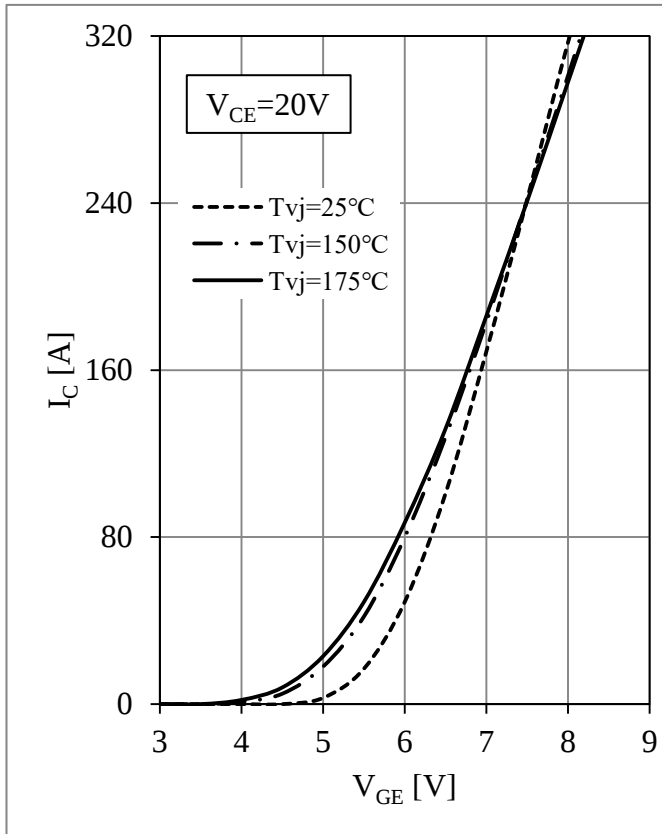
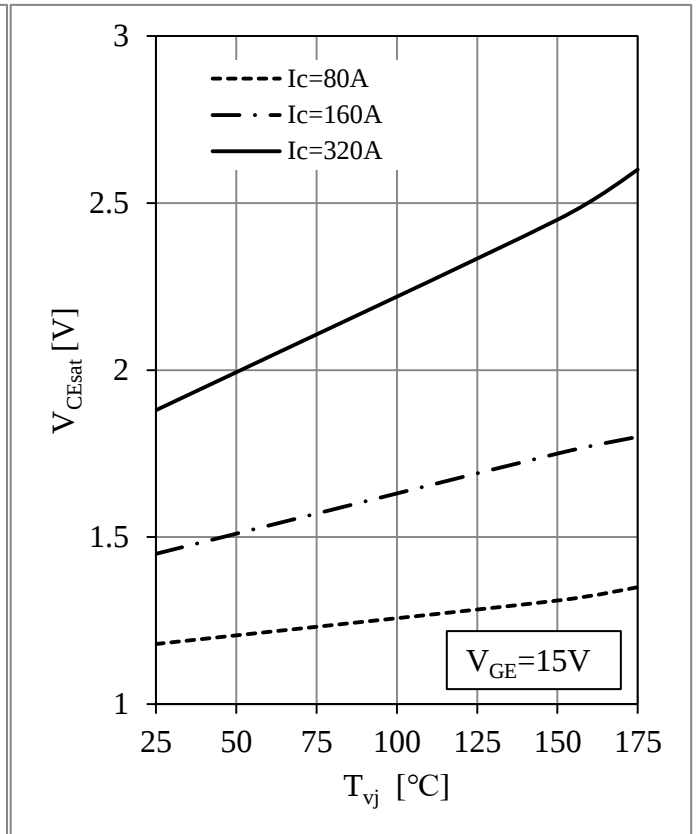
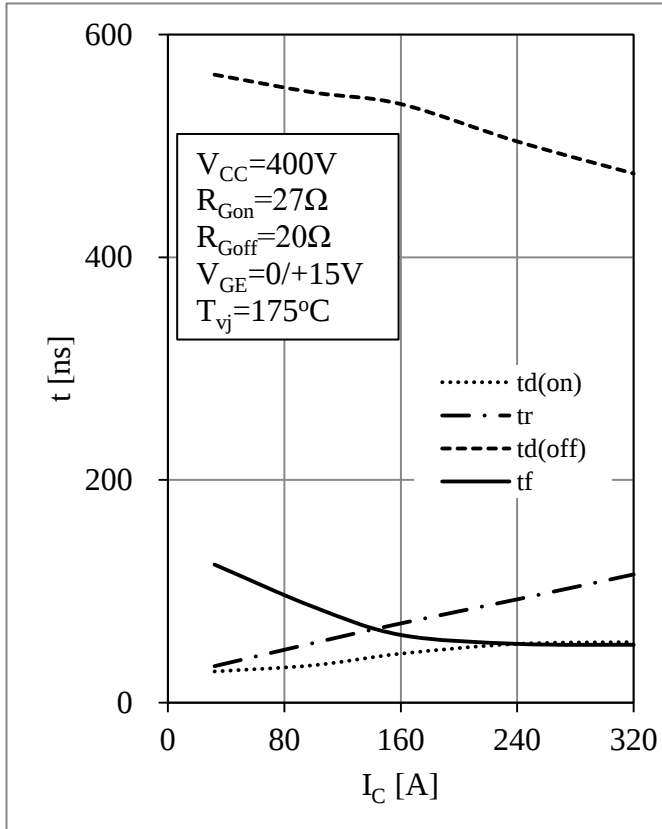
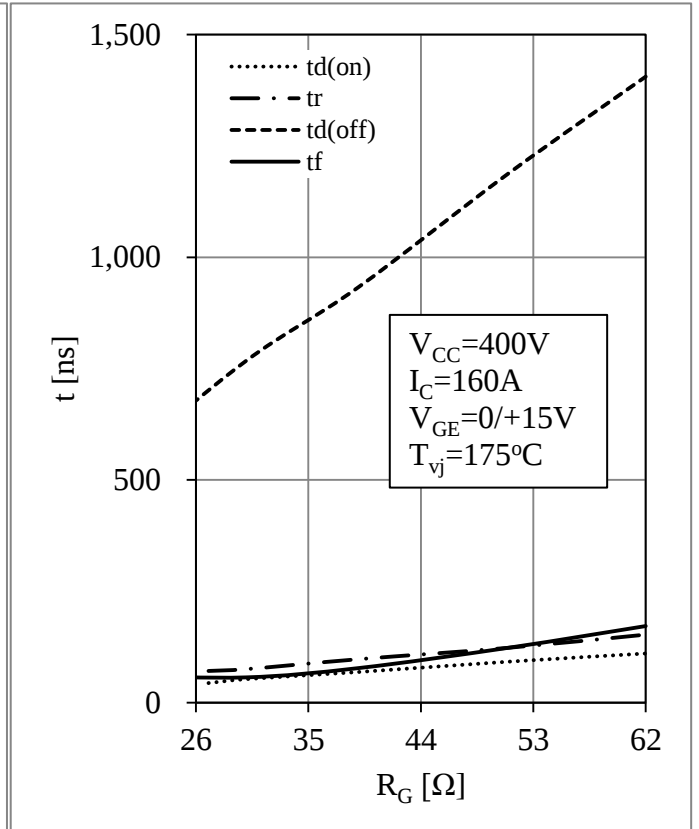
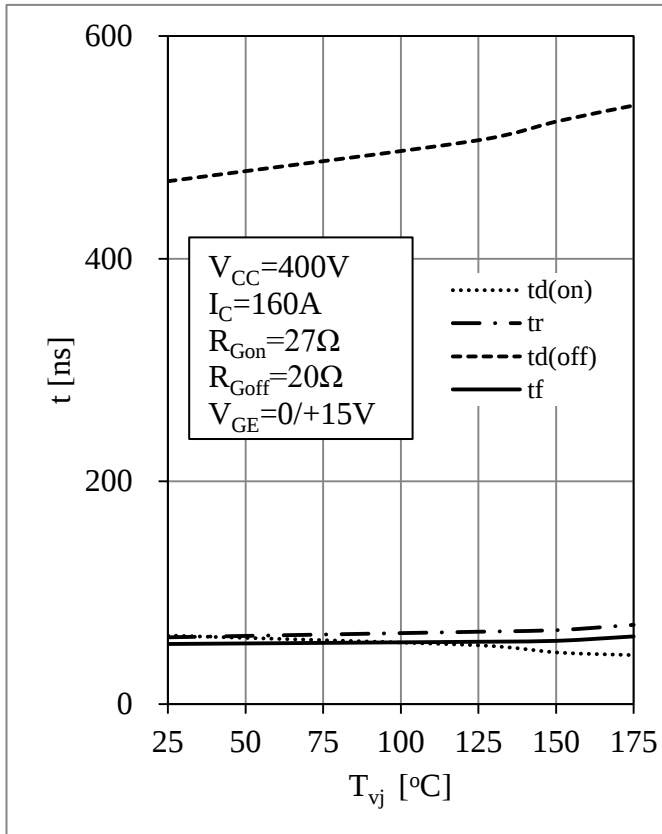
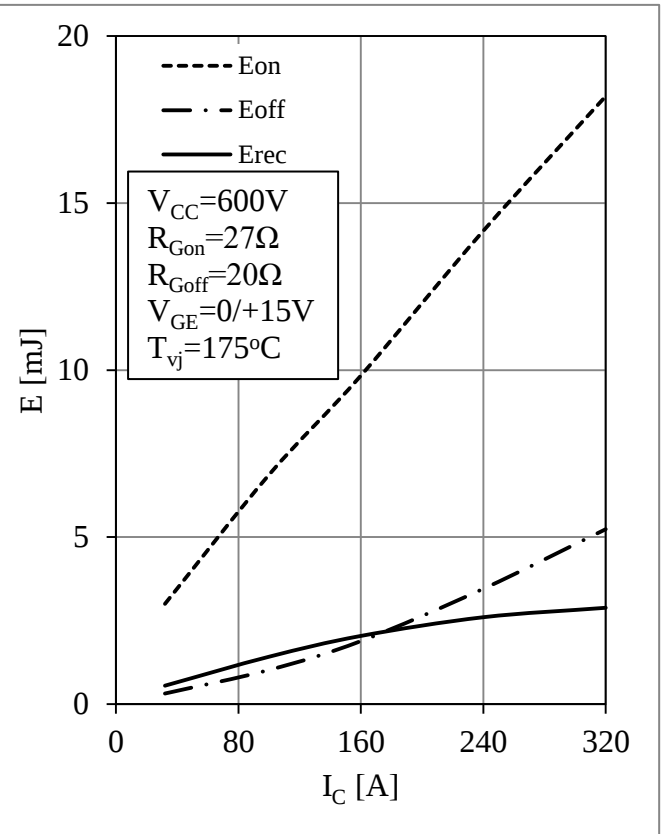
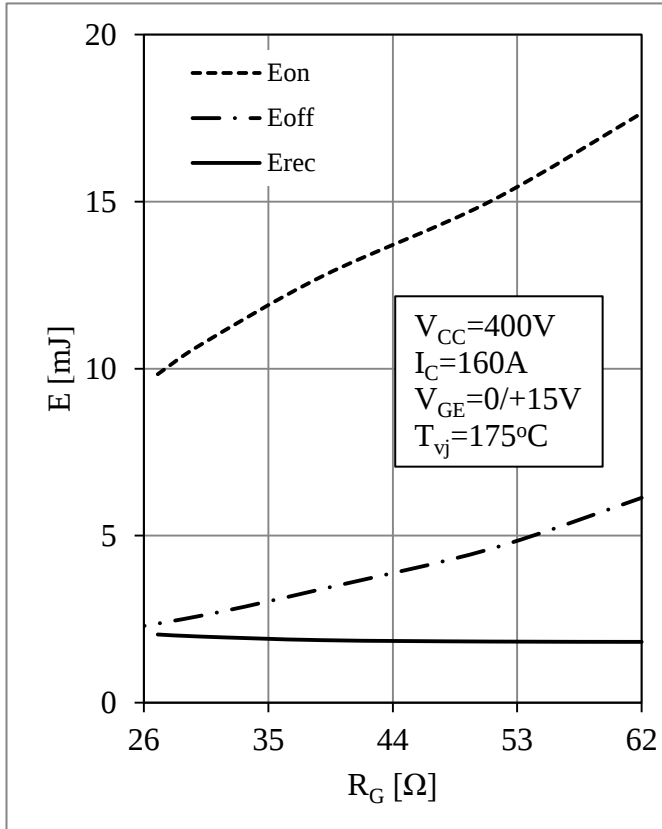
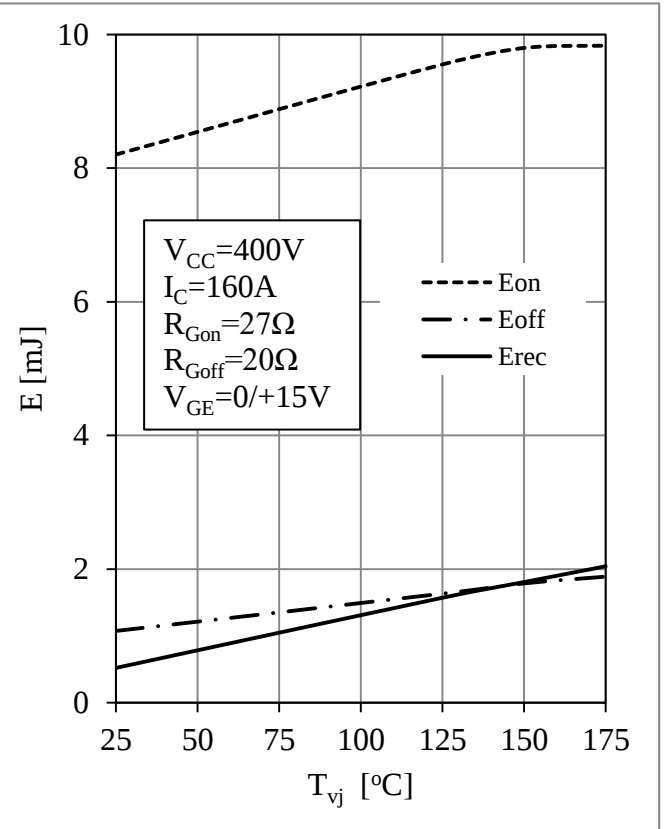


Fig 5. IGBT Transfer Characteristics

Fig 6. Collector-emitter saturation voltage vs T_{vj} Fig 7. IGBT Switching Times vs. I_C Fig 8. IGBT Switching Times vs. R_G

Fig 9. IGBT Switching Times vs. T_{vj} Fig 10. Switching Energy Loss vs. I_C Fig 11. Switching Energy Loss vs. R_G Fig 12. Switching Energy Loss vs. T_{vj}

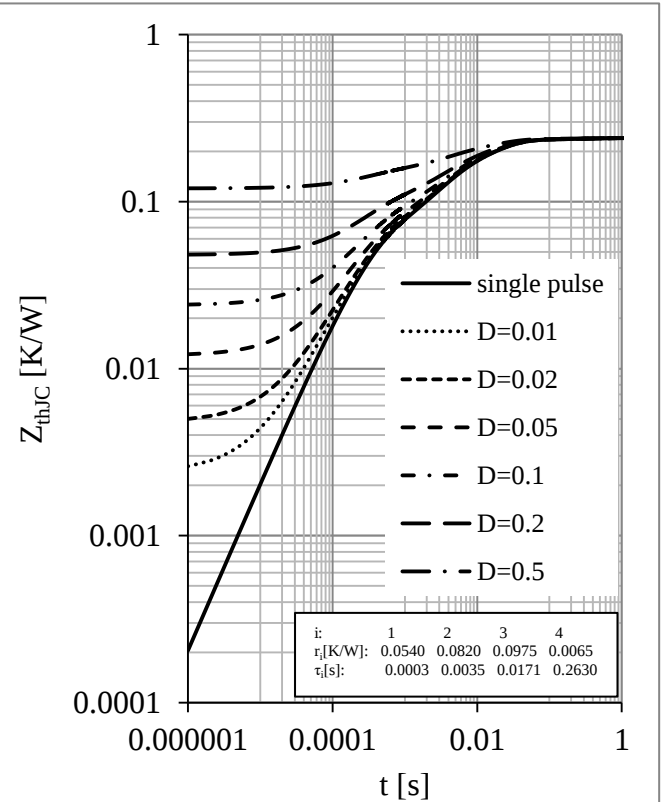
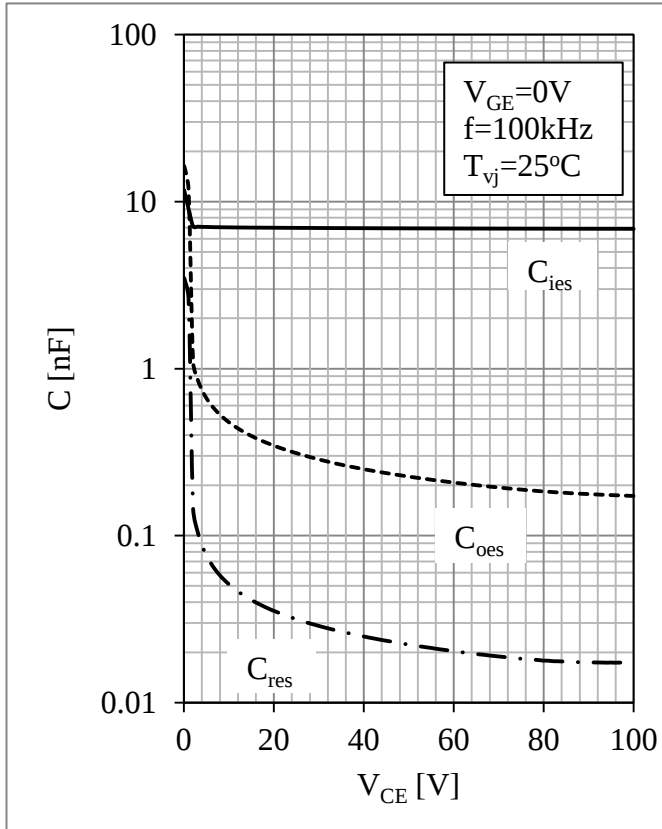
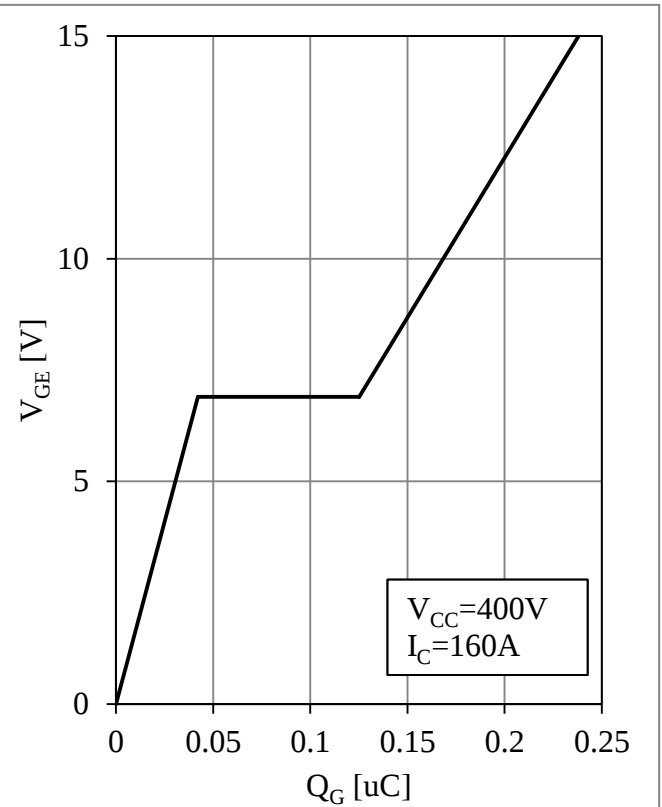
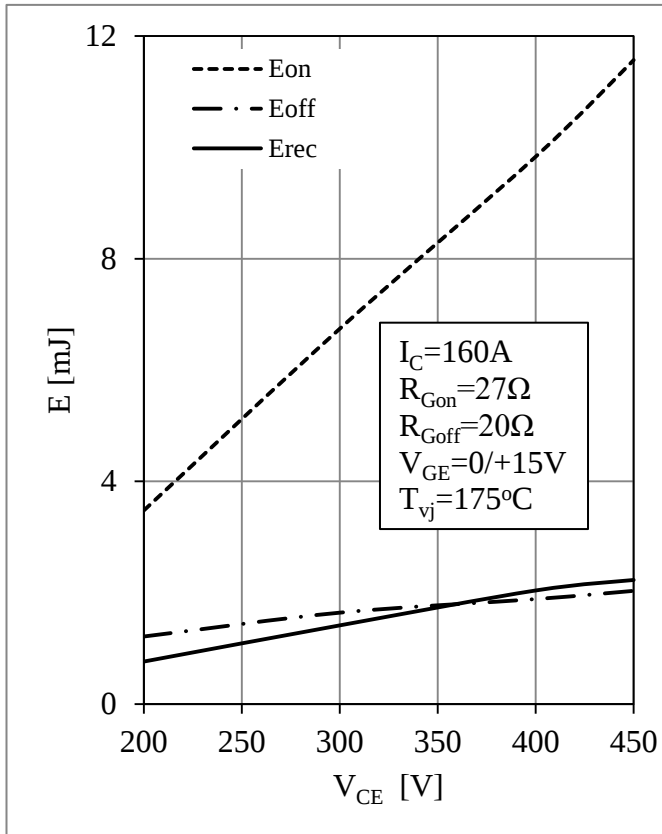


Fig 15. IGBT Capacity Characteristic

Fig 16. IGBT Transient Thermal Impedance

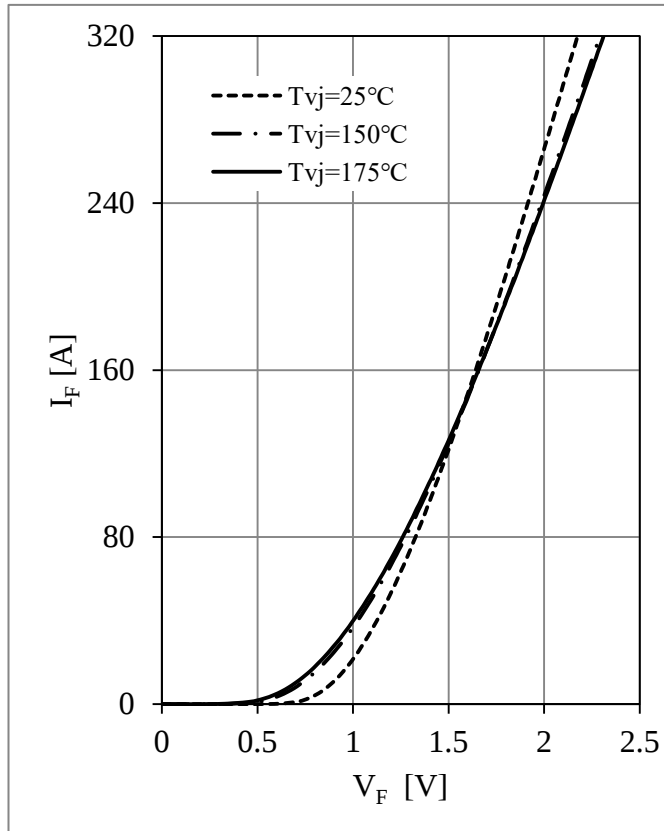
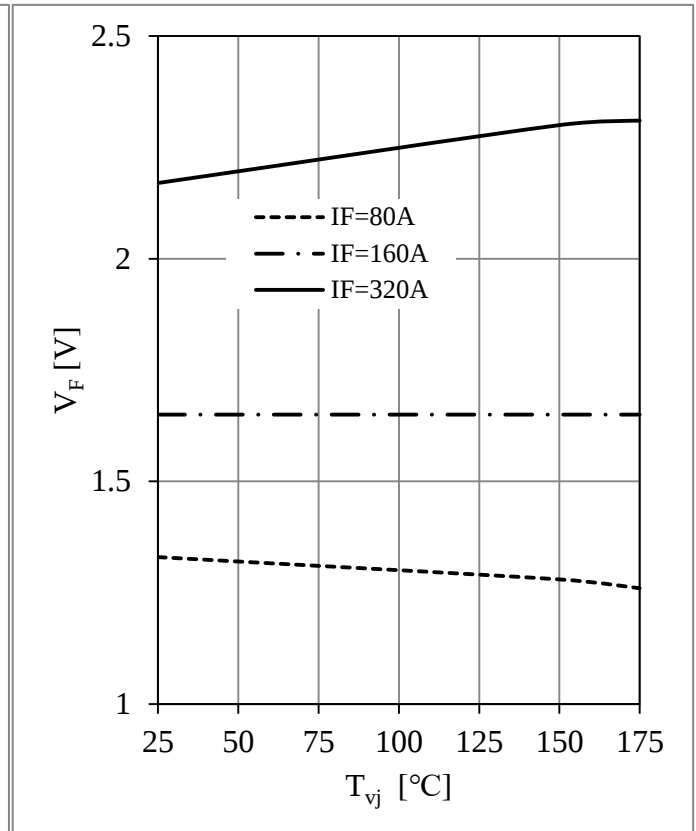
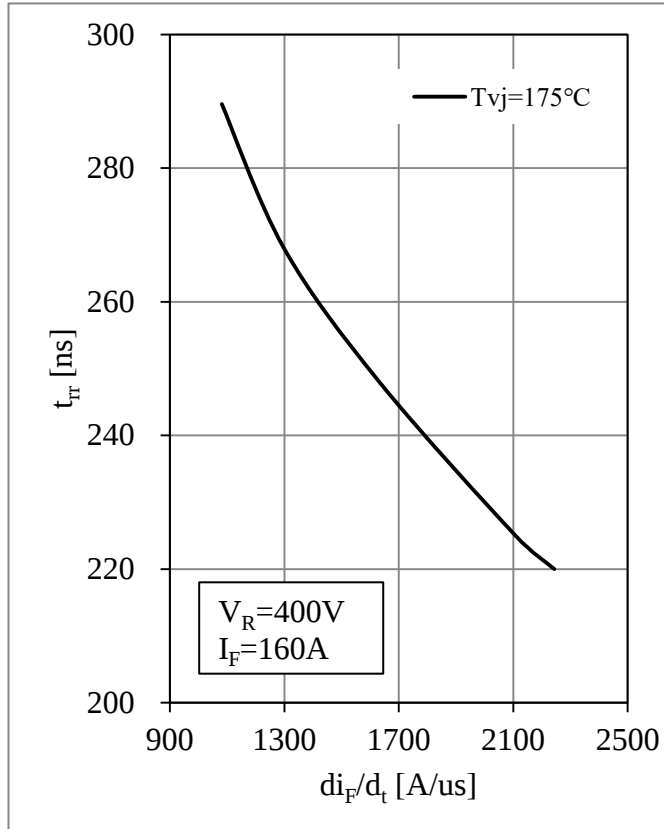
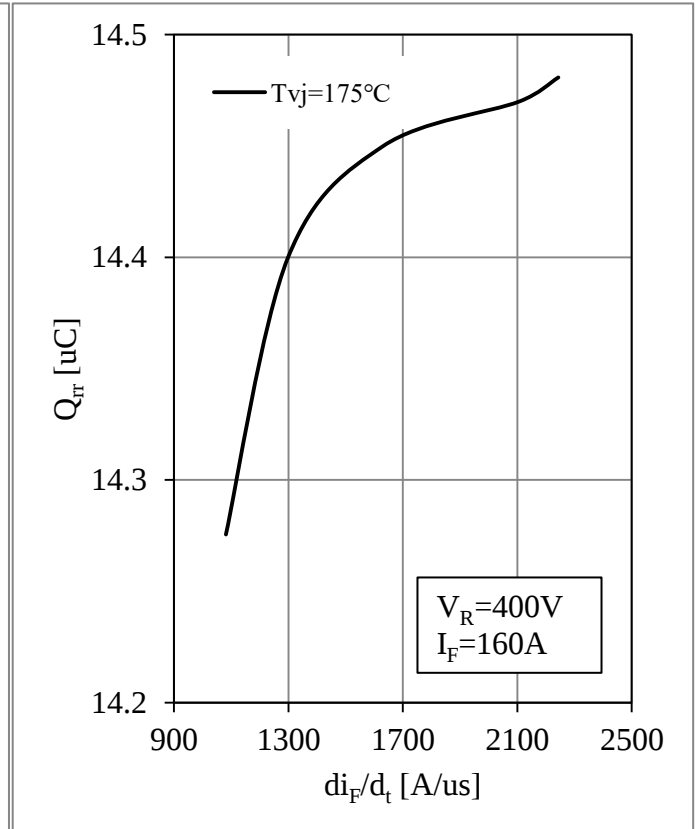


Fig 17. Diode Forward Characteristics

Fig 18. Diode Forward Voltage vs. T_{vj} Fig 19. Reverse Recovery Time vs. di_F/d_t Fig 20. Reverse Recovery Charge vs. di_F/d_t

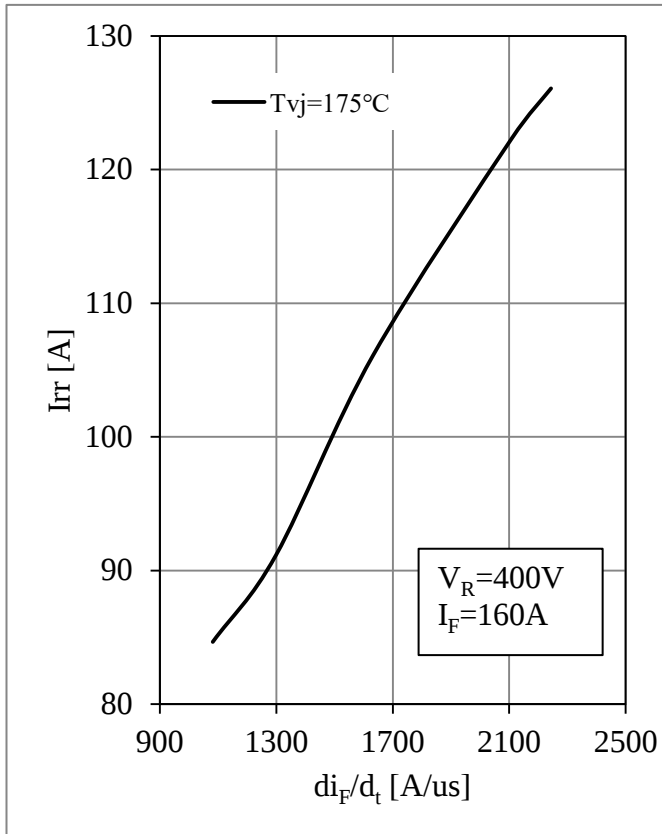
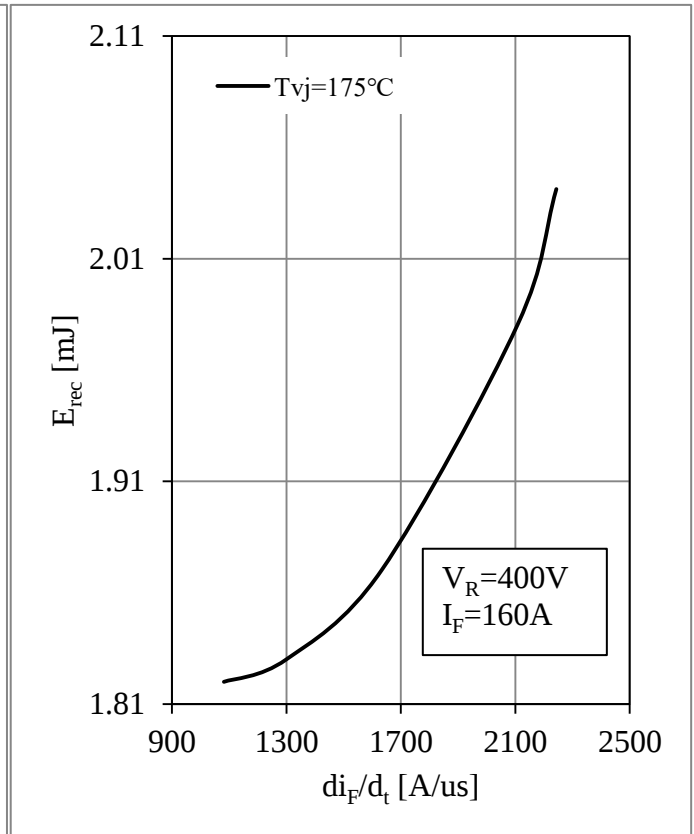
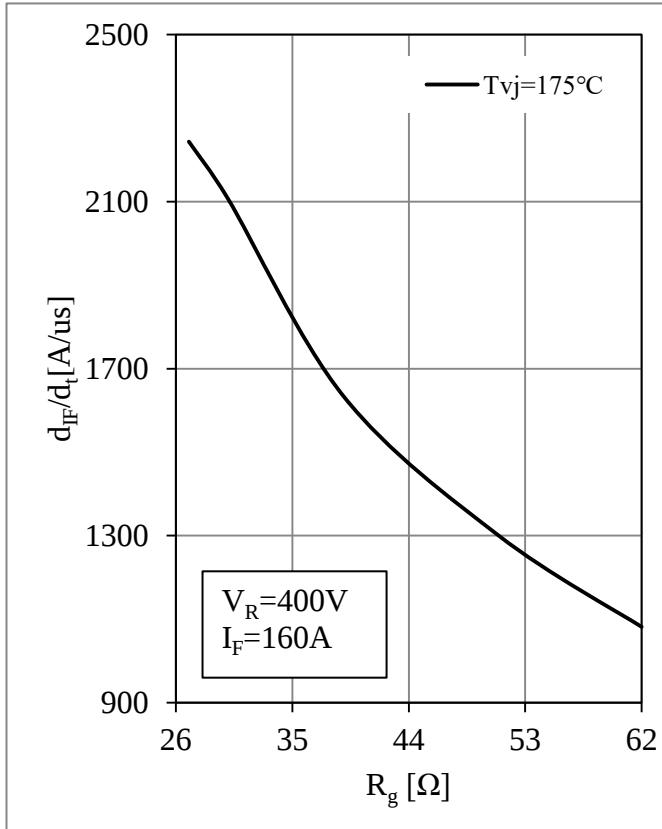
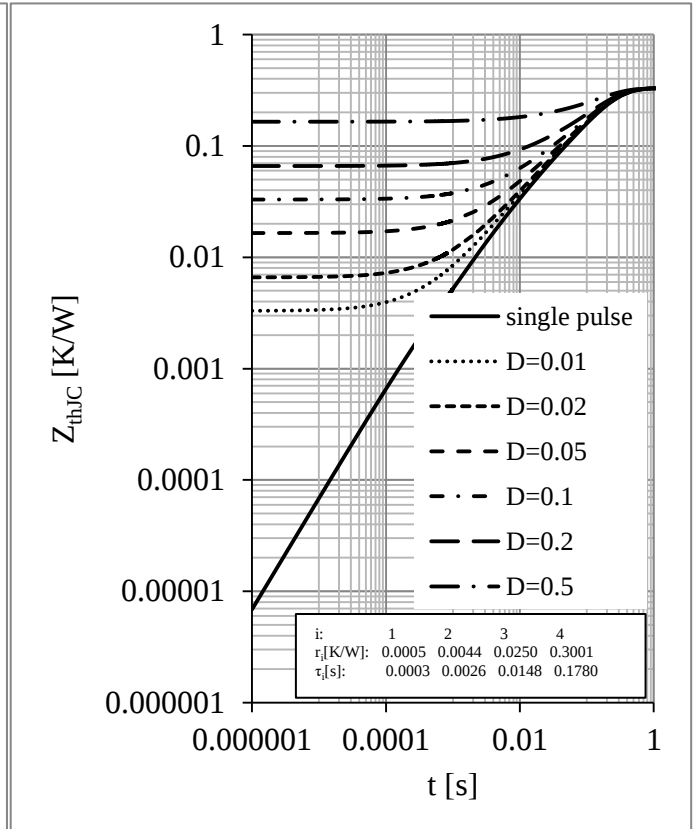
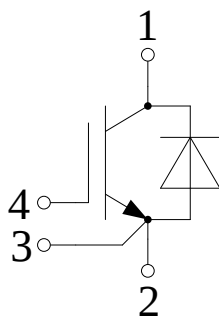
Fig 21. Reverse Recovery Current vs. di_F/d_t Fig 22. Reverse Energy Losses vs. di_F/d_t Fig 23. di_F/d_t vs. R_G 

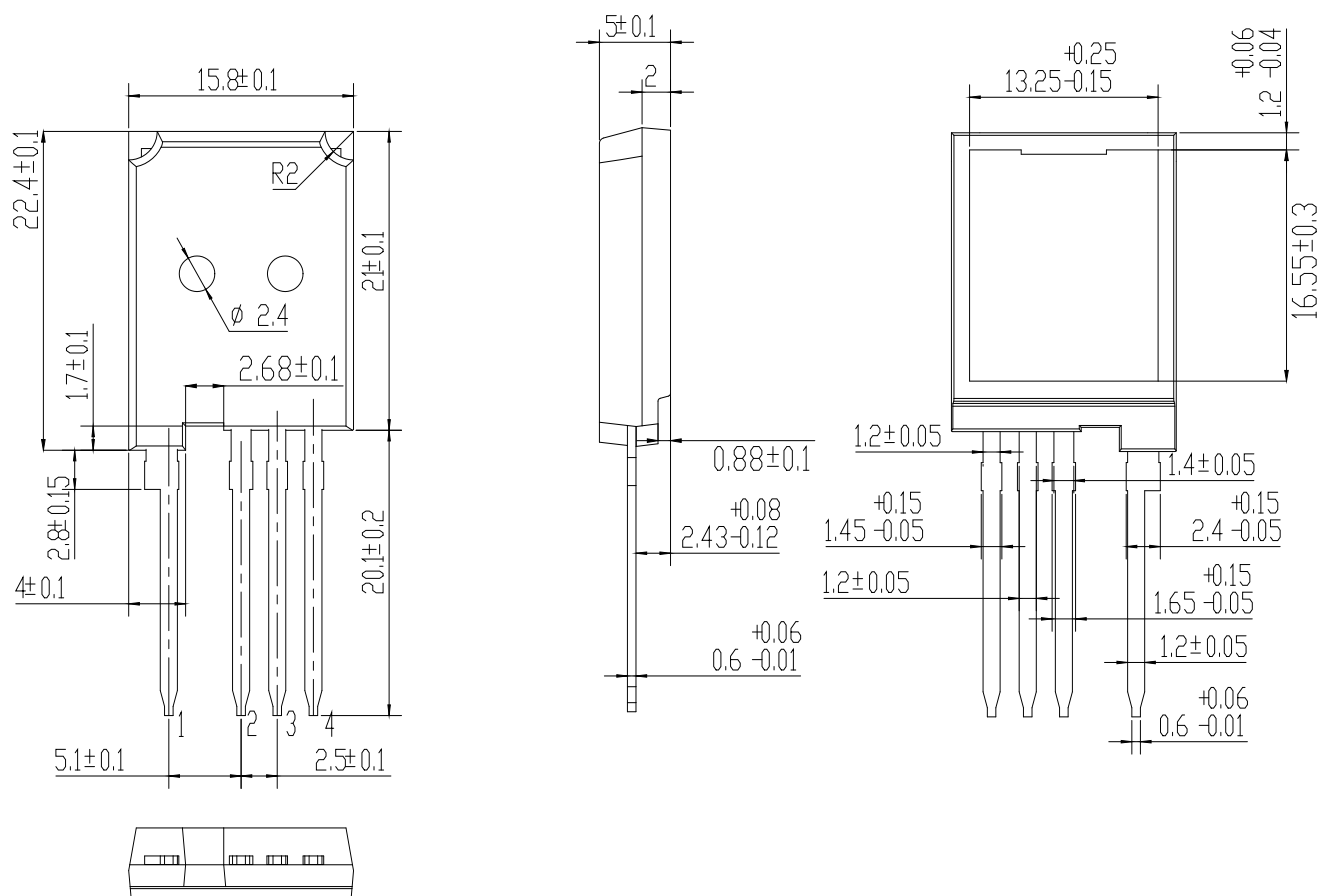
Fig 24. Diode Transient Thermal Impedance

Circuit Schematic



Package Dimensions

Dimensions in Millimeters



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